ELECTRICAL ODECIEICATIONS

Gross Leak Test

**Mechanical Shock** 

Moisture Resistance

**Moisture Sensitivity** 

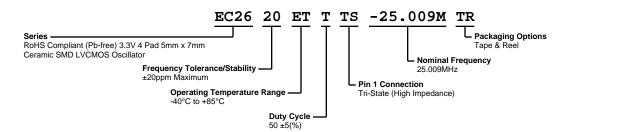
**Temperature Cycling** 

Solderability

Vibration

Resistance to Soldering Heat Resistance to Solvents





| ELECTRICAL SPECIFICATIONS                 |   |  |
|---|---|--|
| Nominal Frequency                         | 25.009MHz   |  |
| Frequency Tolerance/Stability             | ±20ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the<br>Operating Temperature Range, Supply Voltage Change, Ouput Load Change, First Year Aging at 25°C,<br>Shock, and Vibration) |  |
| Operating Temperature Range               | -40°C to +85°C  |  |
| Supply Voltage                            | 3.3Vdc ±10%   |  |
| Input Current                             | 10mA Maximum  |  |
| Output Voltage Logic High (Voh)           | 90% of Vdd Minimum (IOH=-8mA)   |  |
| Output Voltage Logic Low (Vol)            | 10% of Vdd Maximum (IOL=+8mA)   |  |
| Rise/Fall Time                            | 5nSec Maximum (w/15pF Load), 7nSec Maximum (w/30pF Load) (Measured at 20% to 80% of waveform)   |  |
| Duty Cycle                                | 50 ±5(%) (Measured at 50% of waveform)  |  |
| Load Drive Capability                     | 30pF Maximum  |  |
| Output Logic Type                         | CMOS  |  |
| Pin 1 Connection                          | Tri-State (High Impedance)  |  |
| Tri-State Input Voltage (Vih and Vil)     | +0.7Vdd Minimum or No Connect to Enable Output, +0.3Vdd Maximum to Disable Output (High Impedance)  |  |
| Standby Current                           | 10µA Maximum (Disabled Output: High Impedance)  |  |
| RMS Phase Jitter                          | 1pSec Maximum (12kHz to 20MHz offset frequency)   |  |
| Start Up Time                             | 10mSec Maximum  |  |
| Storage Temperature Range                 | -55°C to +125°C   |  |
| ENVIRONMENTAL & MECHANICAL SPECIFICATIONS |   |  |
| ESD Susceptibility                        | MIL-STD-883, Method 3015, Class 1, HBM: 1500V   |  |
| Fine Leak Test                            | MIL-STD-883, Method 1014, Condition A   |  |
| Flammability                              | UL94-V0   |  |

MIL-STD-883, Method 1014, Condition C

MIL-STD-883, Method 2002, Condition B

MIL-STD-202, Method 210, Condition K

MIL-STD-883, Method 1010, Condition B

MIL-STD-883, Method 2007, Condition A

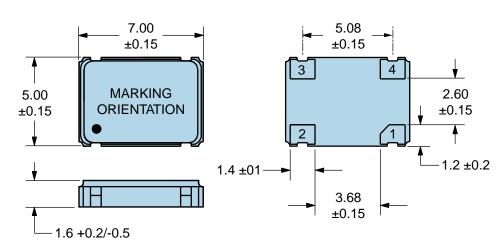
MIL-STD-883, Method 1004

MIL-STD-202, Method 215

MIL-STD-883, Method 2003

J-STD-020, MSL 1

#### **MECHANICAL DIMENSIONS (all dimensions in millimeters)**



| PIN          | CONNECTION                                 |  |
|--------------|--|--|
| 1            | Tri-State                                  |  |
| 2<br>3       | Ground/Case Ground                         |  |
| 3            | Output                                     |  |
| 4            | Supply Voltage                             |  |
| LINE MARKING |  |  |
| 1            | ECLIPTEK                                   |  |
| 2<br>3       | 25.009M                                    |  |
| 3            | XXYZZ<br>XX=Ecliptek Manufacturing<br>Code |  |

Y=Last Digit of the Year

ZZ=Week of the Year

#### Suggested Solder Pad Layout

All Dimensions in Millimeters



All Tolerances are ±0.1



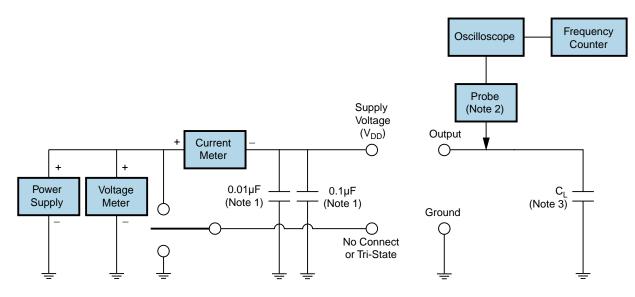
# **CORPORATION**



#### **OUTPUT WAVEFORM & TIMING DIAGRAM**



**Test Circuit for CMOS Output** 



Note 1: An external  $0.1\mu$ F low frequency tantalum bypass capacitor in parallel with a  $0.01\mu$ F high frequency ceramic bypass capacitor close to the package ground and V<sub>DD</sub> pin is required.

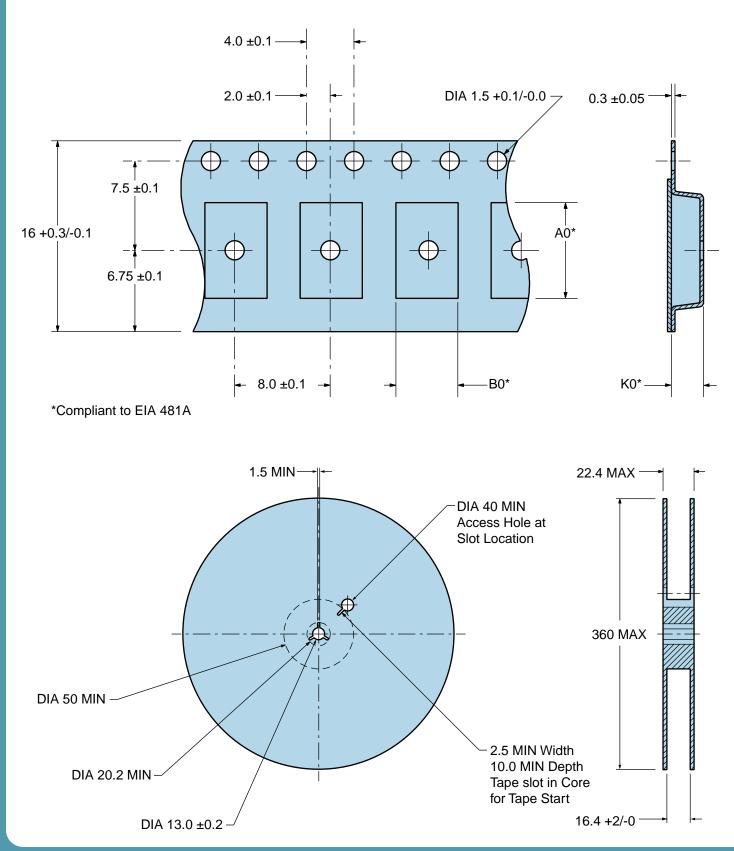
Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $\dot{C}_L$  includes sum of all probe and fixture capacitance.



## Tape & Reel Dimensions

Quantity Per Reel: 1,000 units

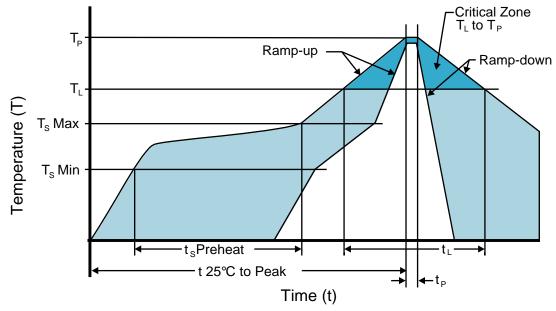


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## **Recommended Solder Reflow Methods**

EC2620ETTTS-25.009M TR



#### **High Temperature Infrared/Convection**

| T <sub>s</sub> MAX to T <sub>L</sub> (Ramp-up Rate)         | 3°C/second Maximum                                |
|---|---|
| Preheat   |   |
| - Temperature Minimum (T <sub>s</sub> MIN)                  | 150°C   |
| - Temperature Typical (T <sub>s</sub> TYP)                  | 175°C   |
| <ul> <li>Temperature Maximum (T<sub>s</sub> MAX)</li> </ul> | 200°C   |
| - Time (t <sub>s</sub> MIN)                                 | 60 - 180 Seconds                                  |
| Ramp-up Rate (T <sub>L</sub> to T <sub>P</sub> )            | 3°C/second Maximum                                |
| Time Maintained Above:                                      |   |
| - Temperature (T∟)  | 217°C   |
| - Time (t∟)   | 60 - 150 Seconds                                  |
| Peak Temperature (T <sub>P</sub> )                          | 260°C Maximum for 10 Seconds Maximum              |
| Target Peak Temperature (T <sub>P</sub> Target)             | 250°C +0/-5°C                                     |
| Time within 5°C of actual peak (t <sub>p</sub> )            | 20 - 40 seconds                                   |
| Ramp-down Rate  | 6°C/second Maximum                                |
| Time 25°C to Peak Temperature (t)                           | 8 minutes Maximum                                 |
| Moisture Sensitivity Level                                  | Level 1   |
| Additional Notes  | Temperatures shown are applied to body of device. |
|   |   |



## **Recommended Solder Reflow Methods**

EC2620ETTTS-25.009M TR



#### Low Temperature Infrared/Convection 240°C

| $T_s$ MAX to $T_L$ (Ramp-up Rate)                | 5°C/second Maximum                                     |
|--|--|
| Preheat  |  |
| - Temperature Minimum (T <sub>s</sub> MIN)       | N/A  |
| - Temperature Typical (T <sub>s</sub> TYP)       | 150°C  |
| - Temperature Maximum (T <sub>s</sub> MAX)       | N/A  |
| - Time (t <sub>s</sub> MIN)                      | 60 - 120 Seconds                                       |
| Ramp-up Rate (T⊾ to T <sub>P</sub> )             | 5°C/second Maximum                                     |
| Time Maintained Above:                           |  |
| - Temperature (T∟)                               | 150°C  |
| - Time (t∟)                                      | 200 Seconds Maximum                                    |
| Peak Temperature (T <sub>P</sub> )               | 240°C Maximum  |
| Target Peak Temperature (T <sub>P</sub> Target)  | 240°C Maximum 1 Time / 230°C Maximum 2 Times           |
| Time within 5°C of actual peak (t <sub>p</sub> ) | 10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time |
| Ramp-down Rate                                   | 5°C/second Maximum                                     |
| Time 25°C to Peak Temperature (t)                | N/A  |
| Moisture Sensitivity Level                       | Level 1  |
| Additional Notes                                 | Temperatures shown are applied to body of device.      |

#### Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

#### **High Temperature Manual Soldering**

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)